

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 108582		APPLICATION NO. New U.S. Patent Application	
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)				APPLICANTS Atsushi OHIDO, Kazuhito YAMASAWA			
				FILING DATE February 9, 2001			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
		JP 4-139093 (w/abstract)	5/13/1992	Japan	1	1	
		JP 6-92796 (w/abstract)	4/5/1994	Japan			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
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EXAMINER				DATE CONSIDERED			
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
<i>[Signature]</i>		US 5 662 740 A	09-02-1997	Yamasawa et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
<i>[Signature]</i>		JP A 5-173102	07-13-1993	Japan			
		EP 0 368 483 A2	05-16-1990	Europe			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>[Signature]</i>		Ferrand et al. "Growth by LPE of ND: YAG single crystal layers for waveguide laser applications." <u>Journal of Crystal Growth</u> . Proc. 10 <sup>th</sup> Int. Conf. On Crystal Growth '92 March 1993 I, Pt. 2, No. 1/4, Amsterdam, NL.					
		Nakajima et al. "A New Improved (YbTbBi) <sub>3</sub> Fe <sub>5</sub> O <sub>12</sub> Epitaxial Thick Film, 8108 I. E. E. E. Trans. On Magnetics 24 (1988) Nov. No. 6, New York, NY, US					
EXAMINER				DATE CONSIDERED <i>4/16/01</i>			
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